

RF-5000 可见-红外反射测量系统

RF-5000 visible infrared reflection measurement system

- RF-5000可见-红外反射测量系统采用远方公司多项专利技术，测量波段范围覆盖380-2500nm，可快速精确测量可见和近红外宽波段范围内光谱反射率，特别适合低反射率的深色样品测量，具备变角光谱反射率测量功能。

The RF-5000 visible infrared reflection measurement system adopts a number of patented technologies of remote companies. The measurement band covers 380-2500nm. It can quickly and accurately measure the spectral reflectance in the wide band range of visible and near-infrared. It is especially suitable for the measurement of dark samples with low reflectivity. It has the function of variable angle spectral reflectance measurement.



特点与优势 Characteristics and advantage

- 30年光谱仪研发生产经验，数十项专利技术，极宽的光谱测量范围，测量精度极高；
30 years of spectrometer R&D and production experience, dozens of patented technologies, extremely wide spectrum measurement range, and extremely high measurement accuracy;
- 测量波段范围覆盖380-2500nm；
The measuring band covers 380-2500nm;
- 灵敏度高，稳定性复现性好，杂散光小，特别适用于较低反射率的深色样品测量；
High sensitivity, good stability and reproducibility, small stray light, especially suitable for measuring dark samples with low reflectivity;
- 可根据实际波长需求，灵活进行分段测试；
It can flexibly conduct segmented testing according to the actual wavelength requirements;
- 支持变角测试。
Support variable angle test.

技术参数 Specifications

型号	RF-5000 可见-红外反射测量系统
照明/测量几何	8/d (球底部开口)
	入射角度可变：8°-60° (经度， @球心)
光谱反射率测量范围	380-2500nm
光源	高性能光源
波长准确度	±0.3nm(380-780nm) ±0.5nm(780-1600nm) ±3nm(1600-2500nm)
带宽	4nm(380-780nm) 9nm(780-1600nm) 15nm(1600-2500nm)
光谱反射率测量范围	0-100%
反射率测量重复性	0.2% (相对标准偏差)
标准板	溯源至 NIM